

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/883,851	MAGLICH, BOGDAN C.	
Examiner Daniel L. Greene Jr.		Art Unit 3663	Page 1 of 2	

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	B	US-5,378,895	01-1995	Cole et al.	250/390.04
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	V	Publications, last accessed 8/10/2005, available @ http://www.silcom.com/~drlny/publications.htm
	W	Design of an Associated Particle Imaging System, Beyerle, et al., Nuclear Instruments and Methods in Physics Research, A299 pp 458-462 (1990)
	X	Data Simulation for the Associated Particle Imaging System, L.N. Tunnell, EGG 11265-3007 UC-905, June 02, 1994

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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Examiner Daniel L. Greene Jr.		Art Unit 3663	Page 2 of 2	

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	K	US-			
	L	US-			
	M	US-			

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